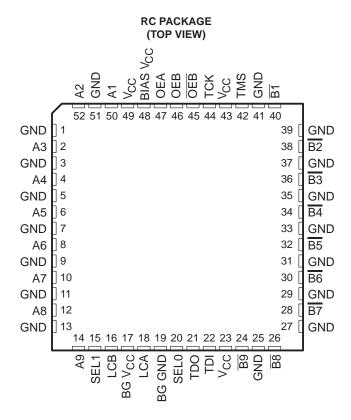
- Compatible With IEEE Std 1194.1-1991 (BTL)
- TTL A Port, Backplane Transceiver Logic (BTL) B Port
- Open-Collector B-Port Outputs Sink 100 mA
- Isolated Logic-Ground and Bus-Ground **Pins Reduce Noise**
- **High-Impedance State During Power Up** and Power Down

- **BIAS V<sub>CC</sub> Minimizes Signal Distortion During Live Insertion or Withdrawal**
- **B-Port Biasing Network Preconditions the** Connector and PC Trace to the BTL **High-Level Voltage**
- **TTL-Input Structures Incorporate Active** Clamping to Aid in Line Termination
- Packaged in Plastic Quad Flatpack



#### description

The SN74FB2031 device is a 9-bit transceiver designed to translate signals between TTL and backplane transceiver logic (BTL) environments. It is specifically designed to be compatible with IEEE Std 1194.1-1991.

The B port operates at BTL-signal levels. The open-collector B ports are specified to sink 100 mA. Two output enables (OEB and  $\overline{OEB}$ ) are provided for the  $\overline{B}$  outputs. When OEB is low,  $\overline{OEB}$  is high, or  $V_{CC}$  is less than 2.1 V, the  $\overline{B}$  port is turned off.

The A port operates at TTL signal levels. The A outputs reflect the inverse of the data at the  $\overline{B}$  port when the A-port output enable (OEA) is high. When OEA is low or V<sub>CC</sub> is less than 2.1 V, the A outputs are in the high-impedance state.



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## description (continued)

Pins are allocated for the 4-wire IEEE Std 1149.1 (JTAG) test bus. TMS and TCK are not connected and TDI is shorted to TDO.

BIAS  $V_{CC}$  establishes a voltage between 1.62 V and 2.1 V on the BTL outputs when  $V_{CC}$  is not connected.

 $BG\ V_{CC}$  and  $BG\ GND$  are the supply inputs for the bias generator.

The SN74FB2031 is characterized for operation from 0°C to 70°C.

#### **Function Tables**

#### **TRANSCEIVER**

	INPUTS		FUNCTION				
OEA	OEB	OEB	FUNCTION				
L	Н	L	A data to B bus				
Н	L	Χ	B data to A bus				
Н	Χ	Н					
Н	Н	L	A data to B bus, B data to A bus				
L	L	Х	Isolation				
L	Χ	Н	เรอเลแอก				

#### STORAGE MODE

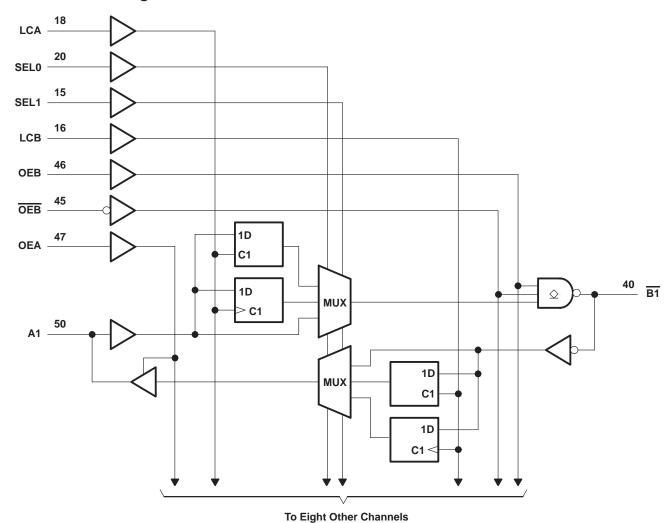
LCA, LCB	RESULT
0	Transparent
1	Latches latched
1	Flip-flops triggered

#### **SELECT**

SEL1	SEL0	MUX A→B	MUX B→A
0	0	Latch	Latch
0	1	Through	Through
1	0	Flip-flop	Flip-flop
1	1	Flip-flop	Latch



## functional block diagram



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	. $-0.5 \text{ V}$ to 7 V
Input voltage range, V <sub>I</sub> : Except B port	. $-1.2 \text{ V}$ to 7 V
B port	-1.2 V to 3.5 V
Voltage range applied to any $\overline{B}$ output in the disabled or power-off state, $V_{O}$	
Voltage range applied to any output in the high state, V <sub>O</sub>	-0.5 V to V <sub>CC</sub>
Input clamp current, I <sub>IK</sub> : Except B port	–40 mA
B port	–18 mA
Current applied to any single output in the low state, IO: A port	48 mA
B port	200 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 1)	44°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51.



## recommended operating conditions (see Note 2)

			MIN	NOM	MAX	UNIT
V <sub>CC</sub> , BIAS V <sub>CC</sub> , BG V <sub>CC</sub>	V <sub>CC</sub> , BIAS V <sub>CC</sub> , Supply voltage BG V <sub>CC</sub>				5.5	٧
V <sub>IH</sub>	High level input veltage		1.62		2.3	V
		Except B port	2			v
V	B p	B port	0.75		1.47	V
VIL	Low-level input voltage Except B po				0.8	V
I <sub>ОН</sub>	High-level output current	A port			-3	mA
lei	Low lovel output ourrent	A port			24	mA
lOL	Low-level output current B port				100	IIIA
TA	Operating free-air temperature	·	0		70	°C

NOTE 2: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS		MIN	TYP <sup>†</sup>	MAX	UNIT	
Viiis	B port	$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA			-1.2	V	
VIK	Except B port	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -40 \text{ mA}$			-0.5	V	
Vон	A port	V <sub>CC</sub> = 4.5 V	$I_{OH} = -1 \text{ mA}$				·	
VOH	A poit	VCC = 4.5 V	$I_{OH} = -3 \text{ mA}$	2.5	3.3			
	A port	V <sub>CC</sub> = 4.5 V	$I_{OL} = 20 \text{ mA}$					
VOL	A poit	VCC = 4.5 V	$I_{OL} = 24 \text{ mA}$		0.35	0.5	V	
VOL	B port	V <sub>CC</sub> = 4.5 V	$I_{OL} = 80 \text{ mA}$	0.75		1.1	V	
	Броп	VCC = 4.5 V	$I_{OL} = 100 \text{ mA}$			1.15		
IĮ	Except B port	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = 5.5 V			50	μΑ	
I <sub>IH</sub> ‡	Except B port	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = 2.7 V			50	μΑ	
. +	Except B port	V <sub>CC</sub> = 5.5 V	V <sub>I</sub> = 0.5 V			-50	μА	
I <sub>IL</sub> ‡	B port	VCC = 5.5 V	V <sub>I</sub> = 0.75 V			-100		
lozh	A port	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$	V <sub>O</sub> = 2.7 V			50	μΑ	
lozL	A port	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$	V <sub>O</sub> = 0.5 V			-50	μΑ	
lozpu	A port	$V_{CC} = 0 \text{ to } 2.1 \text{ V},$	$V_0 = 0.5 \text{ V to } 2.7 \text{ V}$			50	μΑ	
lozpd	A port	$V_{CC} = 2.1 \text{ V to } 0,$	$V_0 = 0.5 \text{ V to } 2.7 \text{ V}$			-50	μА	
loн	B port	$V_{CC} = 0 \text{ to } 5.5 \text{ V},$	V <sub>O</sub> = 2.1 V			100	μА	
los§	A port	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0	-30		-150	mA	
1	A port to B port	V 55V	1- 0			78	A	
Icc	B port to A port	$V_{CC} = 5.5 \text{ V},$	I <sub>O</sub> = 0	7		78	mA	
C <sub>i</sub>		V <sub>I</sub> = 0.5 V or 2.5 V			4.5		pF	
	A port	V <sub>O</sub> = 0.5 V or 2.5 V			8.5			
C <sub>io</sub>	B port per IEEE Std 1194.1-1991	V <sub>CC</sub> = 0 to 5.5 V				6	pF	

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



<sup>‡</sup> For I/O ports, the parameters I<sub>IH</sub> and I<sub>IL</sub> include the off-state output current.

Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

# SN74FB2031 9-BIT TTL/BTL ADDRESS/DATA TRANSCEIVER

SCBS176K - NOVEMBER 1991 - REVISED SEPTEMBER 1999

# live-insertion specifications over recommended operating free-air temperature range

PAR	PARAMETER TEST CONDITIONS			MIN	MAX	UNIT					
I <sub>CC</sub> (BIAS V <sub>CC</sub> )		V <sub>CC</sub> = 0 to 4.5 V	$V_{B} = 0 \text{ to } 2 \text{ V},$ $V_{I} \text{ (BIAS V}_{CC}) = 4.5 \text{ V to } 5.5 \text{ V}$		\\-\ 0 \\\ \\\\\\\\\\\\\\\\\\\\\\\\\\\\		\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	\\ 0 to 2 \\ \\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\		450	
		V <sub>CC</sub> = 4.5 V to 5.5 V	$V_B = 0 \text{ to } 2 \text{ V},$	V) (BIAS V(C) = 4.5 V to 5.5 V		10	μΑ				
Vo	B port	$V_{CC} = 0$ ,	$V_{I}$ (BIAS $V_{CC}$ ) = 5 $V$	$V_{I}$ (BIAS $V_{CC}$ ) = 5 $V$			V				
		$V_{CC} = 0$ ,	$V_B = 1 V$ ,	$V_I$ (BIAS $V_{CC}$ ) = 4.5 V to 5.5 V	-1						
I <sub>O</sub>	B port	$V_{CC} = 0 \text{ to } 5.5 \text{ V},$	OEB = 0 to 0.8 V			100	μΑ				
		$V_{CC} = 0 \text{ to } 2.2 \text{ V},$	OEB = 0 to 5 V			100					

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

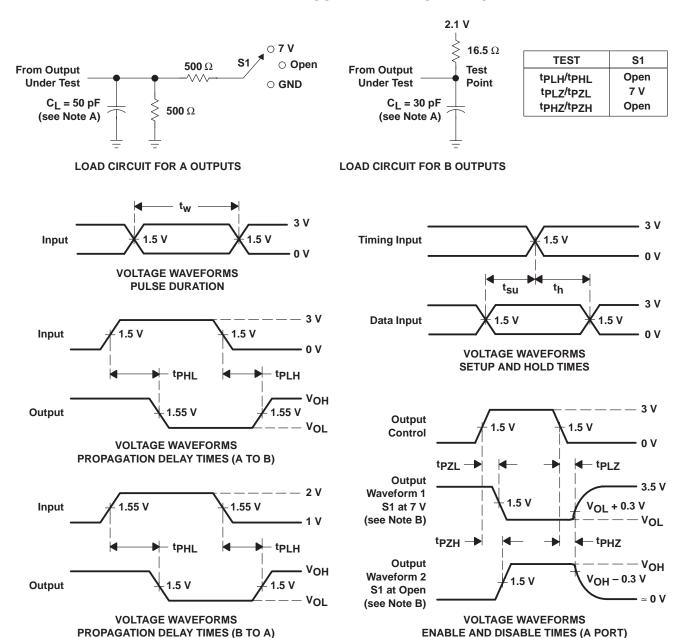
				MIN	MAX	UNIT
fclock	Clock frequency				150	MHz
t <sub>W</sub>	Pulse duration		LCA or LCB	3.3		ns
t <sub>su</sub>		Clock mode	Data before LCA↑	1.4		
	Catura time a	Clock mode	Data before LCB↑	2.8		
	Setup time	Latch mode	Data before LCA↑	1.1		ns
			Data before LCB↑	2.4		
		Clask made	Data after LCA↑	0.6		
		Clock mode	Data after LCB↑	0		
<sup>t</sup> h	Hold time		Data after LCA↑	0.9		ns
		Latch mode	Data after LCB↑	0		

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

P/	ARAMETER	ADAMETED I	FROM (INPUT)		V <sub>0</sub>	CC = 5 V 4 = 25°C	/, }	MIN	MAX	UNIT
		(INPOT)	(001F01)	MIN	TYP	MAX				
	f <sub>max</sub>			150			150		MHz	
	<sup>t</sup> PLH	A	B	3.7	4.5	5.9	3.2	6.6	no	
	<sup>t</sup> PHL	(through mode)	В	2.9	4	5.7	2.6	5.9	ns	
	<sup>t</sup> PLH	A	B	4.1	5	6.5	3.6	7.3	ns	
	<sup>t</sup> PHL	(transparent)	В	3.3	4.5	6.1	3	6.5	115	
	<sup>t</sup> PLH	LCA	B	4.5	5.4	7	3.9	7.8	no	
	<sup>t</sup> PHL	] LCA	В	4	5.1	6.7	3.4	7.4	ns	
	<sup>t</sup> PLH	LCB	А	2.8	3.7	4.7	1.9	6		
	<sup>†</sup> PHL	LCB	А	2.5	3.4	4.9	1.8	5.5	ns	
	tPLH	CEL 1 or CEL 0		2.5	3.8	5.3	1.9	6.3		
t <sub>PHL</sub>	SEL1 or SEL0	A	2.2	3.5	5.1	1.6	5.6	ns		
<sup>t</sup> PLH		CEL4 CEL0	=	4.1	5.3	6.9	3.7	7.8		
	t <sub>PHL</sub>	SEL1 or SEL0	B	3.7	5.2	6.9	3.3	7.7	ns	
	tPLH	B (through mode)	А	3.1	4	5.6	2.2	7.1		
	tPHL			2.6	3.4	4.9	1.4	5.7	ns	
	tPLH	B	Δ.	3.3	4.2	5.9	2.4	7.6		
	tPHL	(transparent)	A	2.8	3.9	5.5	1.8	6.3	ns	
	tPLH		B	3.7	4.6	6.1	3.2	6.7	ns	
	<sup>t</sup> PHL	OEB or OEB		2.9	4.3	5.8	2.5	6.4		
	<sup>t</sup> PZH	OEA	Δ.	2.3	3.1	4.5	1.6	5		
	tPZL	] OEA	А	1.9	2.7	4.1	1.6	4.4	ns	
	<sup>t</sup> PHZ	OEA	٨	2.2	3.1	4.5	1.5	5.2		
	<sup>t</sup> PLZ	OEA	Α	2.5	3.3	4.9	2	5.2	ns	
		A	<u>-</u> В		0.5					
tsk(p)	Pulse skew	B	А		0.3				ns	
	Pulse skew	А			0.2					
tsk(o)		B	A		0.3				ns	
	Transition time, B	outputs (1.3 V to 1.8 V)		0.6	2	2.8	0.4	2.9		
t <sub>t</sub>	Transition time, $\overline{A}$ outputs (1.0% to 90%)				3.5	4.7	0	5.4	ns	
B-port in	put pulse rejection	, , , , , , , , , , , , , , , , , , , ,		0.5			1	-	ns	



#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: TTL inputs: PRR  $\leq$  10 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_f \leq$  2.5 ns,  $t_f \leq$  2.5 ns; BTL inputs: PRR  $\leq$  10 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_f \leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

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